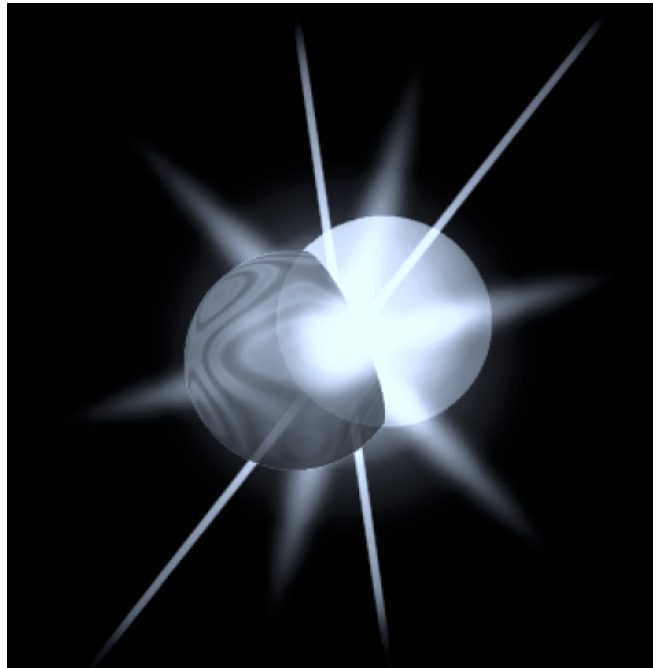


Massively Parallel Computing on the FUZION Chip



Ray McConnell

CTO

PixelFusion plc

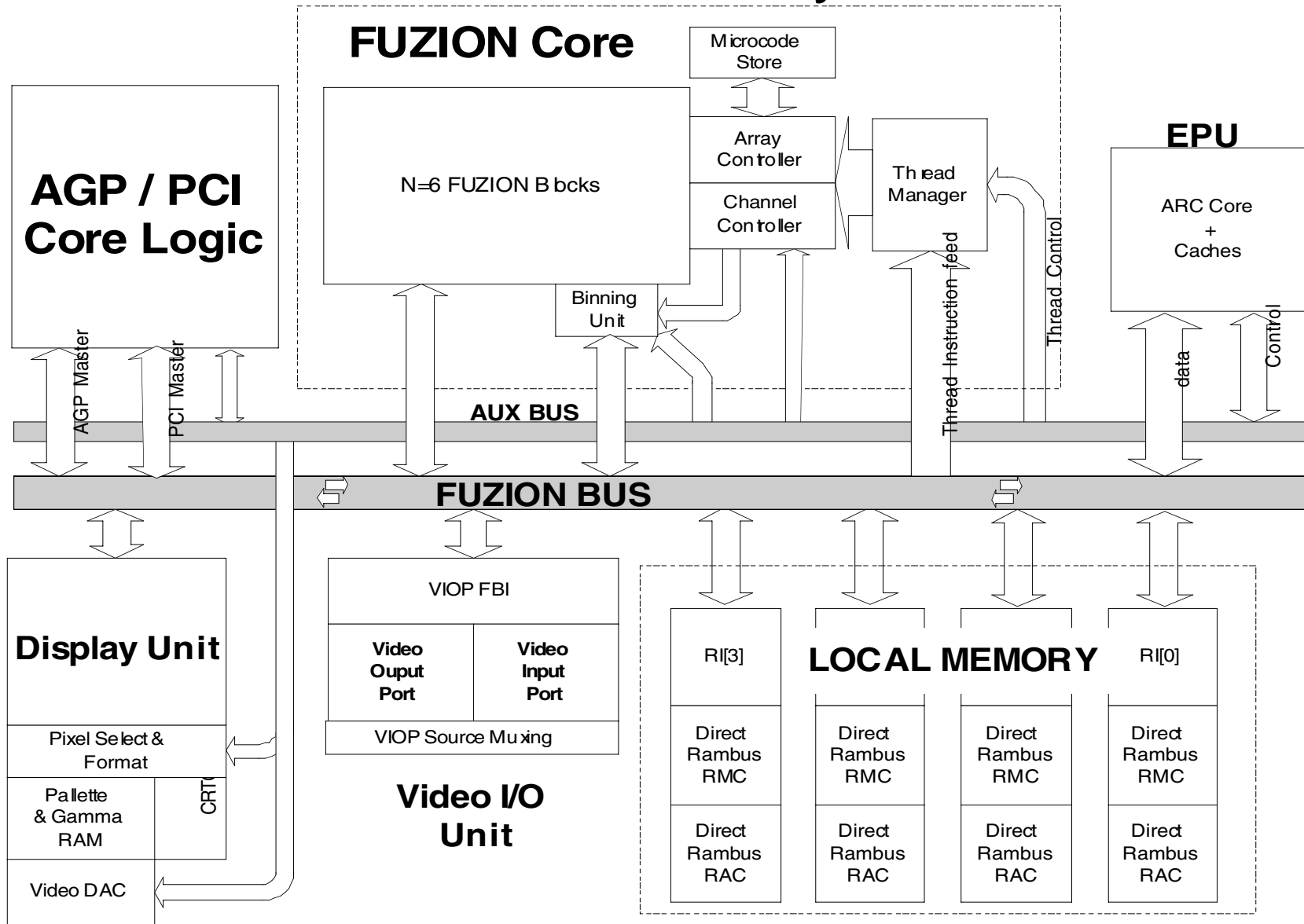
Overview

- History
- Architecture
- Graphics applications
- Future
- Conclusion

Thoroughbred Technology

- Architecture has evolved over 15 years
 - '99 FUZION1 - First Product
 - Evolutionary single/ multi chip solution
 - '97 Pixel Flow
 - 8 bit ALU, Sub pixel composition network
 - '91 Pixel Planes 5
 - 1 bit ALU, Multiple regions connected via crossbar
 - '86 Pixel Planes 4
 - 1 bit ALU, full 512x512 processor instantiation
 - '82 Logic Enhanced Memory Patents filed
 - Assignees: UNC (University of North Carolina)
- Unique patented portfolio
 - 30+ additional patents filed (Architecture+Algorithms)
 - More in process

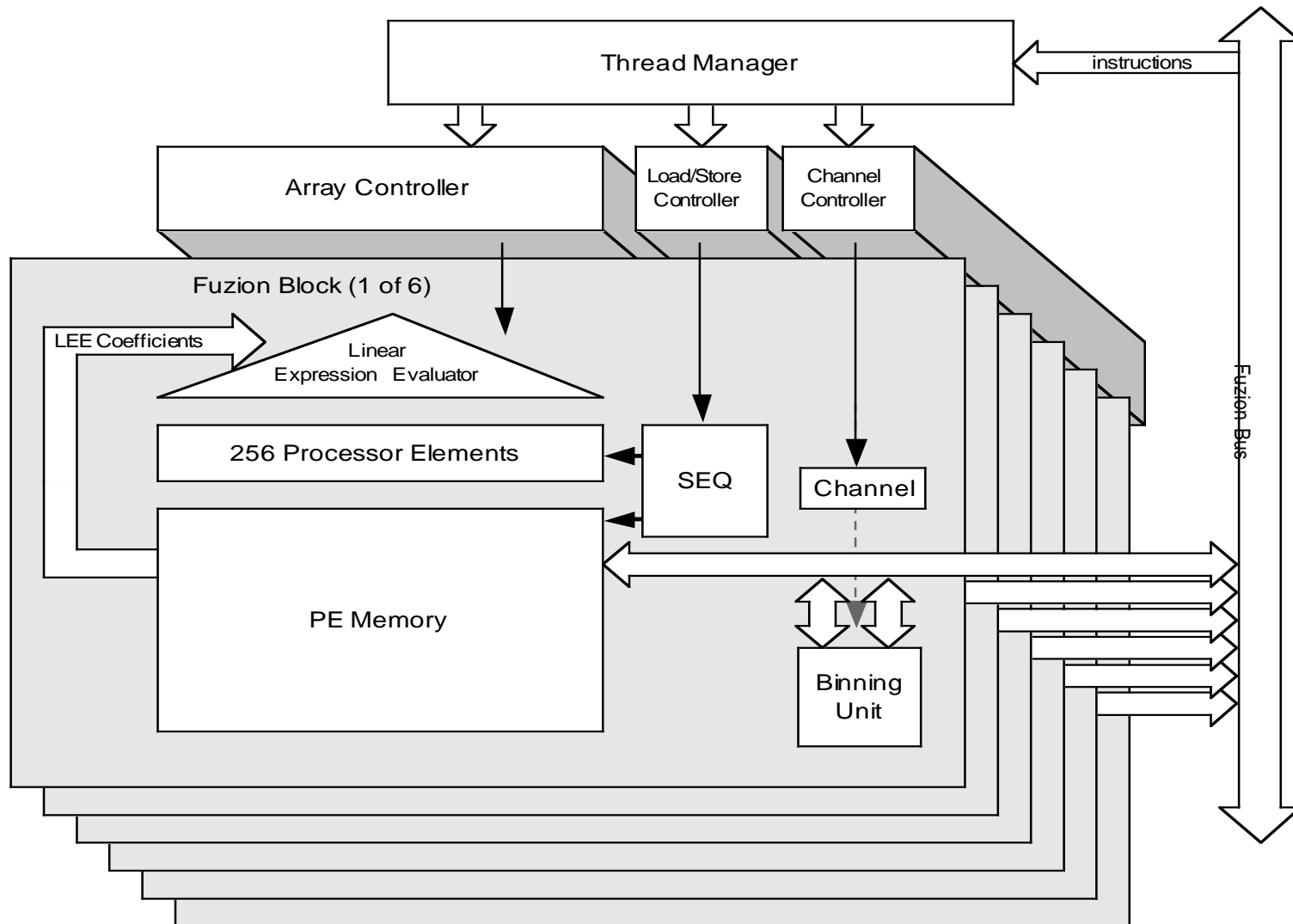
Architecture - System



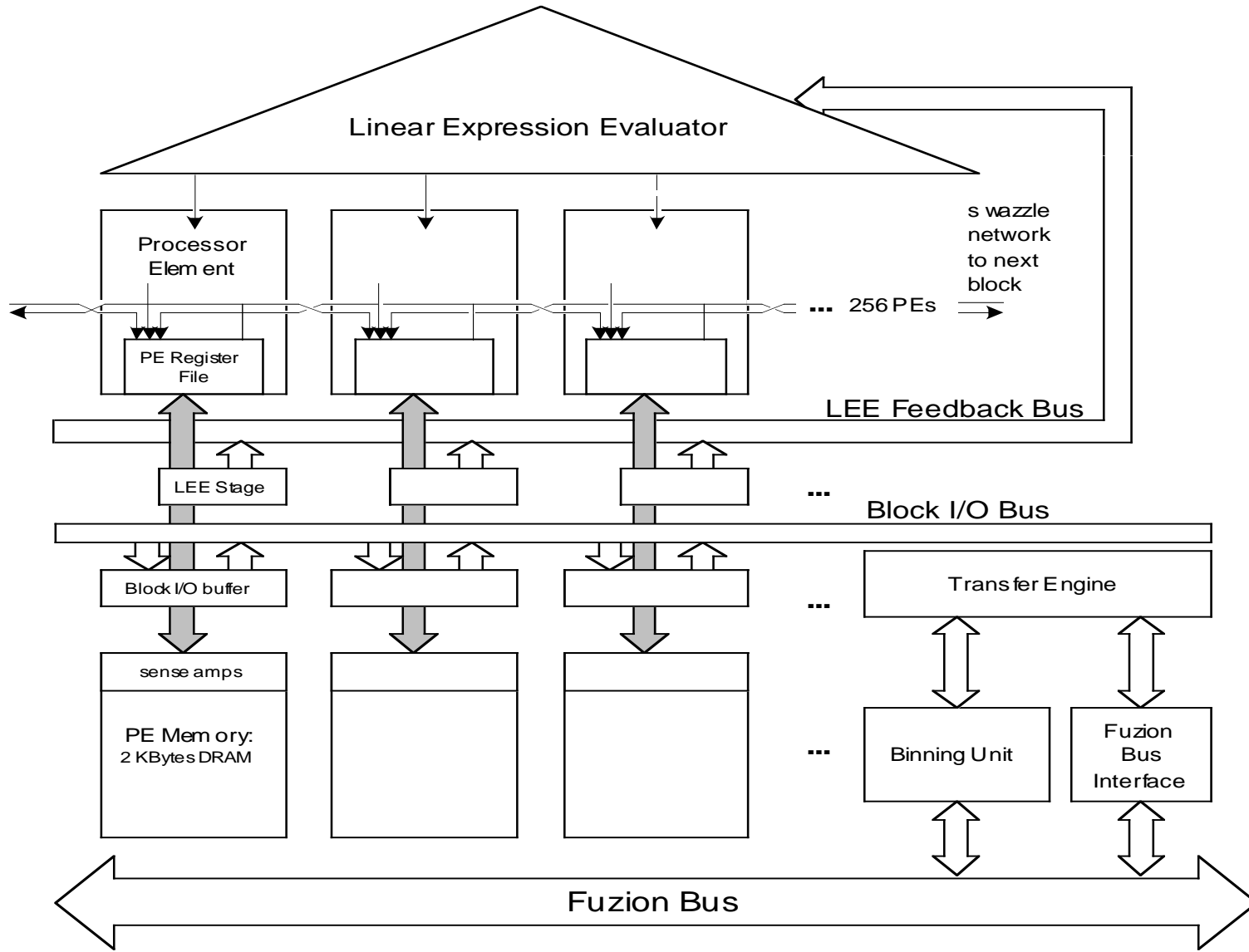
Architecture - System EPU

- Generic 32bit EPU (ARC CPU)
 - Embedded Processor Unit (Synthesised)
 - Data and instruction caches
- Tightly coupled EPU to SIMD Core
 - Low latency multitasking OS (EOS)
 - Exception control
 - Memory management
 - Host protocol management
 - High quality real time emulation of VGA
 - Uses SIMD Core
 - Spare processing cycles on EPU for application extensions

Architecture - Core



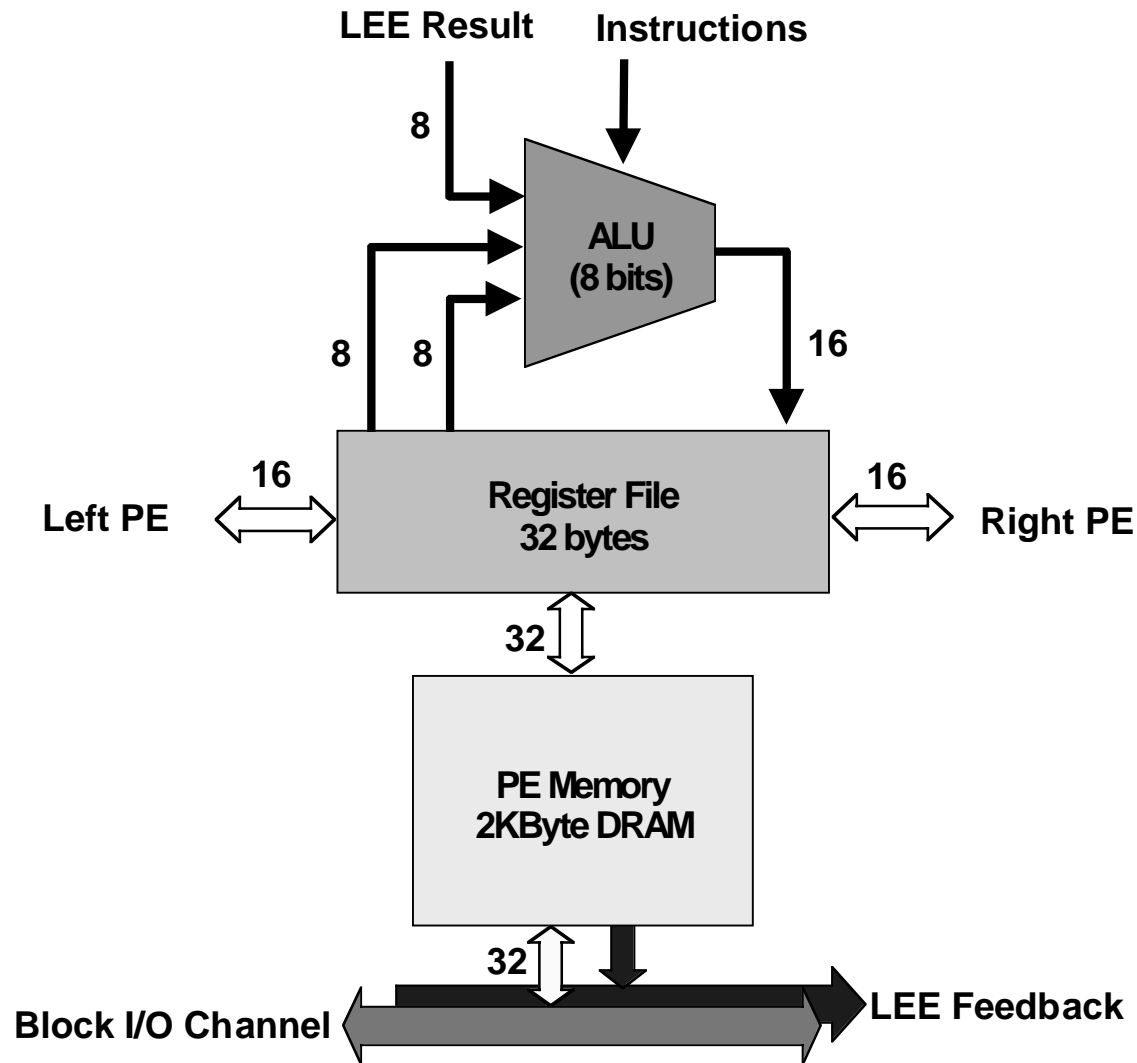
Architecture - Blocks



Architecture - LEE

- Replaces interpolation
 - Evaluates $Ax + By + C$ directly at every PE
- Drawing triangles
 - Evaluate edge equations
- Z- buffering, Gouraud shading
 - All linear in screen space, e.g. $Z = Ax + By + C$
- Perspective- correct texturing
 - Texture coordinates = $Ax + By + C$
- LEE accelerates all rasterization operations
 - Also can be used for data distribution functions

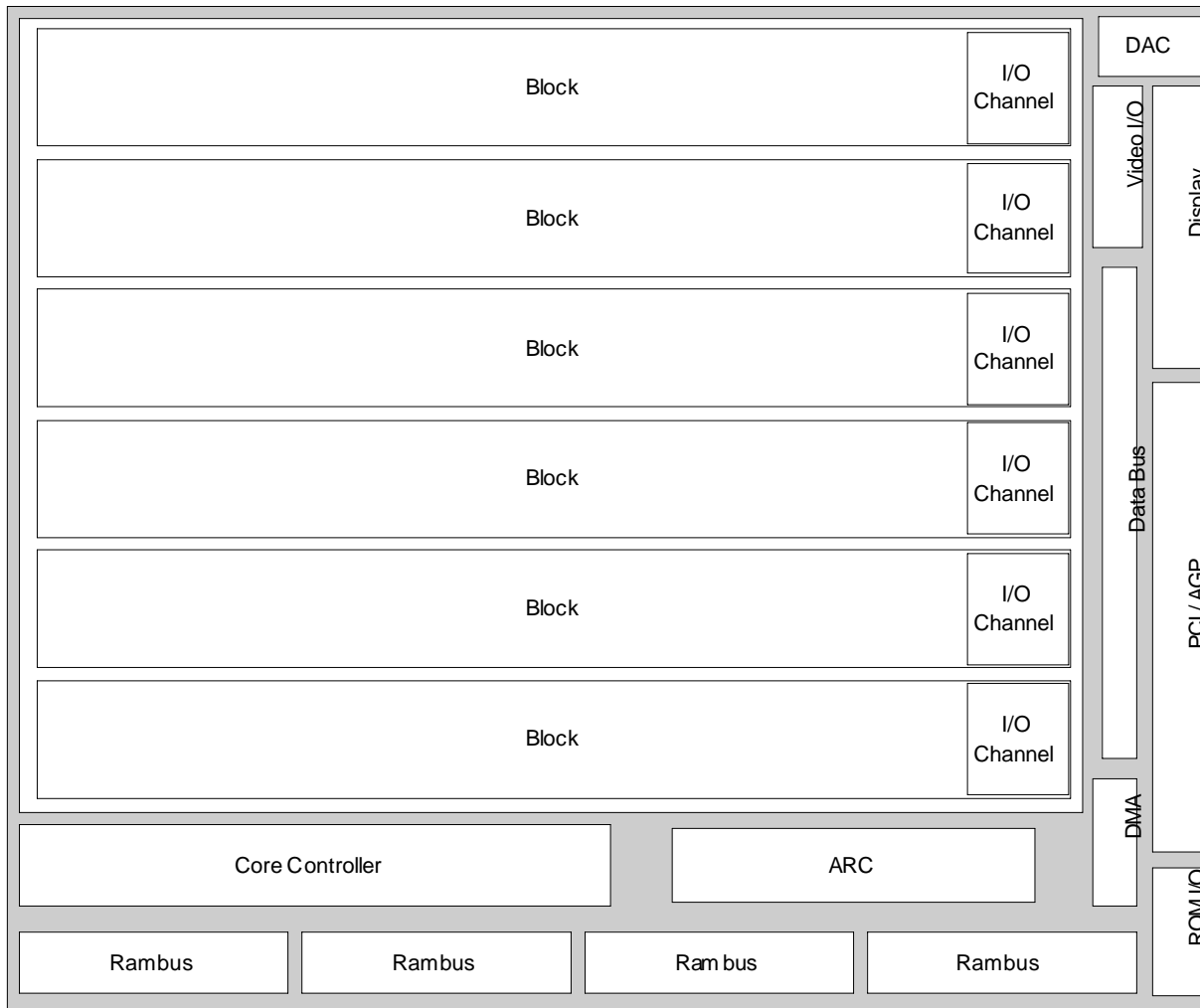
Architecture - PE



Characteristics – Key points

- PE usage efficiency
 - Algorithmic
- PE data flow efficiency
 - Architectural
- I/O Latency efficiency
 - Data driven instruction issue control
- Multithreading
 - Control units interact via semaphores
- Enough PE data workspace
 - 2K Bytes DRAM
 - More complex PE

Characteristics - Silicon



- >500mm²
- 35 Watts
 - Forced Air
- 1036 Pins
 - HPBGA
- ~70M Transistors
- eDRAM process
 - Custom DRAM
- Redundancy
 - PE units + DRAM
 - Yield management

Architecture - Compute numbers

- 1.5 TeraOPS (1.5×10^{12}) 8 bit multiplies and adds
 - LEE + PE
 - 12K bit data-path (8×1536)
- 600 Gigabytes/sec on chip DRAM bandwidth
 - 50k bit wide data-bus (32×1536)
- 1.2 Terabytes/sec PE register file data bandwidth
- 1.2 Terabytes/sec inter PE data bandwidth
- >3 GigaFlops (IEEE compatible)
 - Can be faster with custom format
- 7 GMACs (16×16)
- 150M 3D Transformations/sec
- 50M Tris/sec

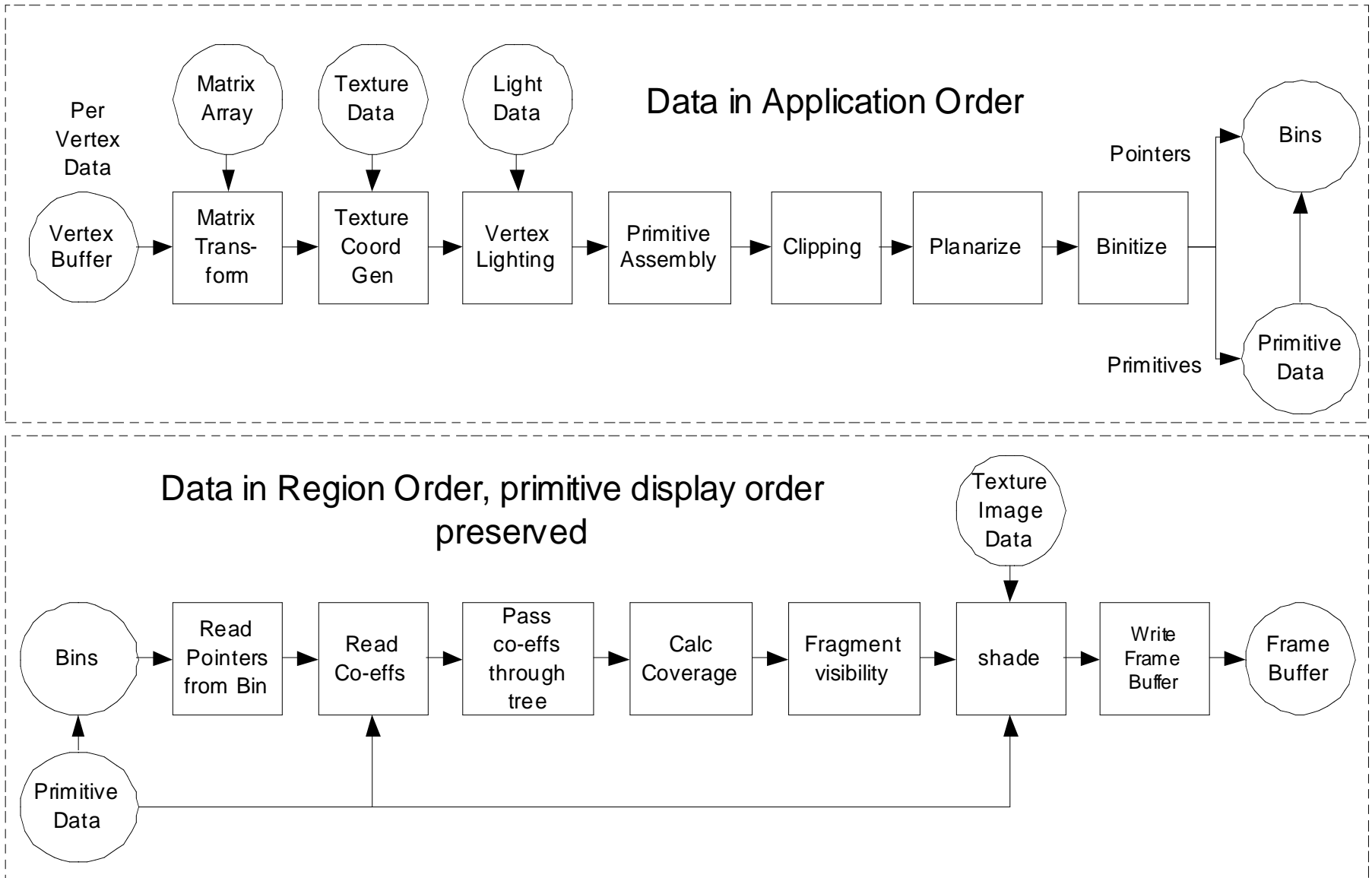
Graphics Applications

- High quality, standard OpenGL
 - 100% compliant v1.2
- High quality, standard Direct 3D
 - 100% compliant DirectX 7
- High quality, standard 2D windows
 - 100% GDI+ compliant
 - Full 256 ROP acceleration
 - Full line & text acceleration with transparency
 - Sophisticated 2D filtering and scaling
- High quality, high resolution MPEG II
- Software is ultimate future-proofing
 - Radical extendibility
 - Completely web revision controlled

SIMD OpenGL

- 100% OpenGL v1.2
 - Region based
 - Efficient Bin sort
 - Bin memory management
 - Efficient with small triangles
 - Blending and texturing is maximally efficient
- Standard extensions
 - Fragment lighting (per pixel shade)
 - Light textures
 - Vertex co-ordinate frames and normal perturbation
 - Multi-sample AA
 - Multi texture and shadow maps

SIMD OpenGL



SIMD OpenGL

- Unbounded API extensions
 - Customisable pipeline for lib function mix-match
 - New primitive types (Curved surfaces)
 - User programmable shaders
- Multiple alpha blended underlay & overlay planes
- In field delivery of API enhancements
 - WWW
- Optional fast/highest-quality anti-aliasing
- Optional geometrical processing
- Scalable software design
 - Will operate on larger/smaller SIMD arrays

Silicon Schedule

- Tapeout Expected by Oct. '99
- First Silicon early December
 - UMC/USIC .25 μ eDRAM Fab
- First Boards Q1 00
- Full System Qualification and optimized OpenGL & Direct3D in Q2 00

Future – Graphics

- Advanced API acceleration
 - Fahrenheit low level (when available)
- Advanced Anti- Aliasing
 - Extremely high resolution coverage sampling
- Advanced 3D effects
 - Depth of field, motion blur, custom shaders, ..
- Advanced shading
 - Torrance Sparrow micro- facet modelling
- Advanced texturing
 - Image based rendering (texture with Z)
- Advanced geometry
 - Function (particles) or map driven
- Volumetric visualization
- 2D within a 3D desktop - natural next step
 - Readable text in perspective

Future - Silicon

- Larger and faster SIMD arrays
- Smaller and cheaper SIMD arrays
- PE extensions
- Multi- chip implementations
- Target Market Variations
 - Core IP licensable
 - Third party IP integration

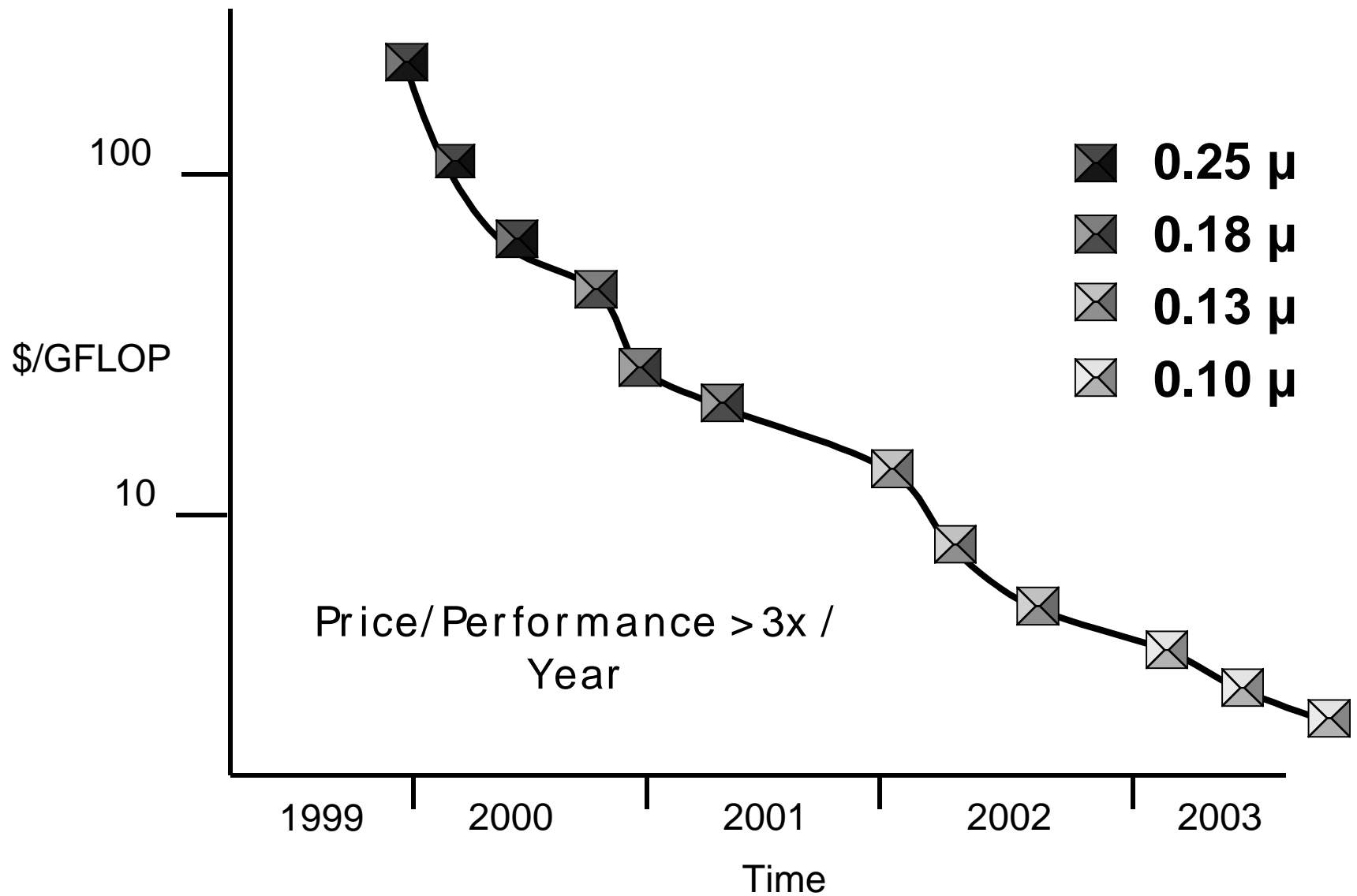
Future - Software Development Kit

- SDK availability
 - Library of software modules
 - 2D, 3D (Gems), Imaging, Numerical etc.
 - EPU C Compiler
 - EOS extensions
 - Simulators
 - PC Farm acceleration
 - Assemblers
 - Debuggers
 - Hierarchical views of PE register/memory
 - Performance monitors
 - hardware assisted
- SIMD C++ scheduled for '00
 - Syntax extensions
 - Explicit Multi-threading

Future - Applications

- Widening application space
 - Advanced Signal, 2D Image and Video processing
 - Advanced motion detection for video compression
 - Fast fuzzy data search/convolution (DNA sequencing)
 - Machine vision
 - Artificial neural networks
 - Encryption/Decryption/Compression/Decompression
- Can make use of installed graphics hardware
 - CAD acceleration
 - PC Farm super-computing

Future price/performance



Conclusion

- Open functionality and re-use of software
 - Real applications, real markets
 - Performance compares with hardwired functions
 - Market scope larger than 3D graphics
 - Software will port rapidly to future generations
- Roadmap into future, beyond 0.13u technologies
 - Verification task massively simplified with replication
 - Highly regular custom silicon layout
 - Deep sub-micron design barrier solution
 - 5k man/gate/day productivity (from ground zero)
 - Higher on next generations
 - Highly parallel embedded test (Using EPU)
- Redundancy for yield management
 - Cost reduction on large die